

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	8634	(data with (select selecting selection) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22
L15	1126	((sample specimen wafer die) with (matrix array) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L16	183	((pca (principal adj component adj analysis)) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L17	81	(model with maintenance with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L18	537	((product sample specimen wafer die defect error fault) with (classing classifying classification categorizing categorize category categorization) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L19	66	l14 and l15	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L20	12	l14 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L21	15	l14 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L22	45	l14 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L23	30	l15 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L24	0	l15 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L25	6	l15 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L26	0	l16 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L27	1	l16 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L28	2	l17 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L29	1	l14 and l15 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22

L30	0	l14 and l15 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L31	1	l14 and l15 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L32	0	l14 and l15 and l16 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L33	0	l14 and l15 and l16 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L34	0	l14 and l15 and l17 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L35	1454	((data near3 (select selecting selection) near3 (module routine sub\$routine)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22
L36	167	((sample specimen wafer die) near3 (matrix array) near3 (module routine sub\$routine)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L37	48	((pca (principal adj component adj analysis)) near3 (module routine sub\$routine)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L38	11	(model near3 maintenance near3 (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L39	125	((product sample specimen wafer die defect error fault) near3 (classing classifying classification categorizing categorize category categorization) near3 (module routine sub\$routine)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:26
L40	1	l35 and l36	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L41	0	l35 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L42	0	l35 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L43	2	l35 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L44	0	l36 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L45	0	l36 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L46	0	l36 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27

L47	0	l37 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L48	0	l37 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L49	2	l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:31
L50	0	l35 and l36 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L51	0	l35 and l36 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L52	0	l35 and l36 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L53	0	l35 and l37 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L54	0	l35 and l37 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L55	0	l35 and l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L56	0	l35 and l36 and l37 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L57	0	l35 and l36 and l37 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L58	0	l35 and l37 and l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:30
L59	0	l35 and l36 and l37 and l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:30
L60	352656	(industrial manufacturing plasma etch etching) near3 process	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L61	93	l60 and l35	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L62	49	l60 and l36	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L63	6	l60 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32

L64	3	160 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L65	36	160 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L66	0	160 and 136 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L67	0	160 and 136 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L68	0	160 and 136 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L69	0	160 and 135 and 136	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L70	0	160 and 135 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L71	0	160 and 135 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L72	0	160 and 135 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L73	0	160 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L74	0	160 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L75	2	160 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L76	0	160 and 135 and 136 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L77	0	160 and 135 and 136 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L78	0	160 and 135 and 136 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L79	0	160 and 135 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L80	0	160 and 135 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34

L81	0	160 and 135 and 136 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L82	0	160 and 135 and 136 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L83	0	160 and 135 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
L84	0	160 and 135 and 136 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
L85	0	160 and 135 and 136 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
S1	10	("5658423" "5864773" "6153115" "6192826" "6419846" "6442445" "6521080" "20020104832" "20020119668" "20030055523").pn.	US-PGPUB; USPAT	OR	OFF	2004/12/21 10:31
S2	2318	principal adj component adj analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/30 06:50
S3	271	(principal adj component adj analysis) and ((industrial or plasma or manufacturing) adj process)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/21 10:33
S4	677	(principal adj component adj analysis) and ((identify identifying identification identifiable determine determining determination determinable identified determined detect detecting detection detectable) with (error fault flaw defect anomaly malfunction erroneous faulty flawed defective anomolous malfunctioning))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S5	157	S4 and ((plasma industrial manufacturing wafer etch etching) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:15
S6	104	S5 and (predict predicted prediction predictable predicting forecast forecasting forecasted)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:16
S7	2447	(principal adj component) and ((identify identifying identification identifiable determine determining determination determinable identified determined detect detecting detection detectable) with (error fault flaw defect anomaly malfunction erroneous faulty flawed defective anomolous malfunctioning))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:15

S8	369	S7 and ((plasma industrial manufacturing wafer etch etching) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:16
S9	195	S8 and (predict predicted prediction predictable predicting forecast forecasting forecasted)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:17
S10	162	S9 and (compute computing computation calculate or claculating calculation calculable computed calculated) and (category catagorizing catagorized sort sorted sorting correlate correlated correlating correlation collate collating collated collation)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:25
S11	102	S10 and (residue residual)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:26
S12	101	S11 and (single singular)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:28
S13	97	S12 and (matrix array matrices)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:34
S14	81	S13 and vector	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:41
S15	11	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:50
S16	59	("5658423").URPN.	USPAT	OR	OFF	2004/12/23 10:55
S17	9	("5121337" "5288367" "5479340" "5552016" "5658423" "5862060" "5885472" "6060328" "6153115").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:56
S18	11	("6238937").URPN.	USPAT	OR	OFF	2004/12/23 10:57
S19	9	("5121337" "5288367" "5479340" "5658423" "5862060" "5885472" "6060328" "6153115" "6238937").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:57
S20	7	("5121337" "5288367" "5479340" "5658423" "5862060" "6238937" "6419846").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:58
S21	1	("6564114").URPN.	USPAT	OR	OFF	2004/12/23 10:58
S22	9	("5121337" "5288367" "5479340" "5658423" "5862060" "6153115" "6238937" "6368879" "6419846").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:58
S23	0	("6582618").URPN.	USPAT	OR	OFF	2004/12/23 10:50
S24	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:51

S25	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S13	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:51
S26	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S12	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S27	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S11	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S28	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S10	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S29	1	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S9	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S30	6	("5658423").URPN. and S14	USPAT	OR	ON	2004/12/23 10:55
S31	1	("5121337" "5288367" "5479340" "5552016" "5658423" "5862060" "5885472" "6060328" "6153115").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:56
S32	3	("6238937").URPN. and S14	USPAT	OR	ON	2004/12/23 10:57
S33	2	("5121337" "5288367" "5479340" "5658423" "5862060" "5885472" "6060328" "6153115" "6238937").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:57
S34	3	("5121337" "5288367" "5479340" "5658423" "5862060" "6238937" "6419846").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:59
S35	0	("6564114").URPN. and S14	USPAT	OR	ON	2004/12/23 10:58
S36	3	("5121337" "5288367" "5479340" "5658423" "5862060" "6153115" "6238937" "6368879" "6419846").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:03
S37	7	("5467883" "6675137" "6582618" "6564114" "6549864" "6419846" "6238937" "5658423").PN. and S14	USPAT	OR	ON	2004/12/23 11:12
S38	320	438/5.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:22
S39	558	700/90.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S40	448	700/95.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S41	467	700/108.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13

S42	236	700/109.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S43	319	700/110.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S44	448	700/117.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S45	1131	700/121.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S46	499	702/117.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S47	211	702/118.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S48	104	702/121.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S49	839	702/182.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S50	676	702/183.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S51	372	702/185.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S52	516	702/189.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S53	58	702/196.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S54	218	438/8.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S55	251	438/9.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S56	96	438/5.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23
S57	80	438/8.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23

S58	97	438/9.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23
S59	28	700/90.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S60	75	700/95.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S61	155	700/108.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S62	90	700/109.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S63	98	700/110.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S64	74	700/117.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S65	281	700/121.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S66	23	702/117.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S67	19	702/118.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S68	8	702/121.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S69	149	702/182.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S70	133	702/183.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25

S71	71	702/185.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S72	59	702/189.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S73	5	702/196.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S74	4	S56 and S4	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S75	4	S57 and S4	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S76	0	S56 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S77	1	S57 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S78	5	S58 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S79	0	S59 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S80	0	S60 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S81	1	S61 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S82	0	S62 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S83	1	S63 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:31
S84	1	S64 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S85	3	S65 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S86	0	S66 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28

S87	0	S67 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S88	0	S68 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S89	0	S69 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S90	1	S70 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:31
S91	0	S71 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S92	0	S72 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S93	0	S73 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S94	14	("5130936" "5133046" "5148378" "5237518" "5267277" "5465321" "5548378" "5629872" "5642296" "5661666" "5680409" "5715178" "5726915" "6219626").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 11:32
S95	4	("6415276").URPN.	USPAT	OR	OFF	2004/12/23 11:35
S96	10	("5467883" "6675137" "6582618" "6564114" "6549864" "6419846" "6238937" "5658423" "6415276" "20030109951").pn.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:47
S97	158	jahns.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S98	0	jahns-gary.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S99	0	zhang-y.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S100	0	palladino-a.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S101	69	palladino.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S102	8231	zhang.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S103	0	zhang-yixin.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S104	0	palladino-anthony.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S105	57	(jahns zhang palladino).in. and ((principal adj component adj analysis) pca)	US-PGPUB; USPAT	OR	ON	2004/12/29 09:50
S106	1	"5711843".pn.	USPAT	OR	OFF	2004/12/23 11:56

S107	92	((industrial or manufacturing or production or plasma) near3 process) and ((fault or flaw or defect or malfunction) near4 (detect\$3 or determin\$5 or discover\$3)) and ((principal adj component adj analysis) pca)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 09:56
S108	16697	((process procedure method) near3 (error fault flaw defect malfunction) near3 (detect detecting detection determine determining determination))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 14:28
S109	107	S108 and (pca (principal adj component adj analysis))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 14:27
S110	313	((industrial manufacturing plasma etching) near3 (process procedure method) near3 (error fault flaw defect malfunction) near3 (detect detecting detection determine determining determination))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 06:43
S111	30	(pca (principal adj component adj analysis)) and (((industr\$3 manufactur\$3 assembl\$3 produc\$4) near3 (process procedure)) with (defect\$3 fault flaw error malfunction\$3) with (detect\$3 determin\$5 locat\$3 find\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/30 08:18
S112	5	("6521080" "6368975" "5864773" "5658423" "20030136511").pn.	US-PGPUB; USPAT	OR	ON	2004/12/30 07:09
S113	21	("5274572" "5305221" "5319580" "5386373" "5406502" "5453156" "5459668" "5465321" "5479340" "5486995" "5526293" "5528510" "5548528" "5566092" "5570300" "5642296" "5646870" "5655110" "5658423" "5659467" "5680409").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/30 07:18
S114	28	("5864773").URPN.	USPAT	OR	OFF	2004/12/30 07:17
S115	6	("4312732" "5653894" "5711843" "5885472" "5966586" "6017414").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/30 07:18
S116	3	("6368975").URPN.	USPAT	OR	OFF	2004/12/30 07:18
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S118	1	("6521080").URPN.	USPAT	OR	OFF	2004/12/30 07:19
S119	2	("5274572" "5305221" "5319580" "5386373" "5406502" "5453156" "5459668" "5465321" "5479340" "5486995" "5526293" "5528510" "5548528" "5566092" "5570300" "5642296" "5646870" "5655110" "5658423" "5659467" "5680409").PN. and S111	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 07:13

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S123	3	("4312732" "5288367" "5653894" "5658423" "5711843" "5885472" "5966586" "6017414" "6153115" "6368975" "6381008" "6413867").PN. and S111	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/30 07:16
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S136	27	"702"/\$.ccls. and (pca (principal adj component adj analysis)) and (process with ((error flaw defect fault malfunction) near5 (detect detecting detection determine determining determination determined detected)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 10:24

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1 Recent experiences in the industrial exploitation of principal component analysis based fault detection methods

Lennox, B.;

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2 A new fault detection and diagnosis method based on principal component analysis in multivariate continuous processes

Yang Yinghua; Lu Ningyun; Wang Fuli; Ma Liling;

Intelligent Control and Automation, 2002. Proceedings of the 4th World Congress on, Volume: 4, 10-14 June 2002

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3 Multivariate statistics and neural networks in process fault detecti

Martin, E.B.; Morris, A.J.;

Qualitative and Quantitative Modelling Methods for Fault Diagnosis, IEE Colloquium, 24 Apr 1995

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1 Spatial characterization of wafer state using principal component analysis of optical emission spectra in plasma etch

White, D.A.; Boning, D.; Butler, S.W.; Barna, G.G.;

Semiconductor Manufacturing, IEEE Transactions on , Volume: 10 , Issue: 1 , 1997

Pages:52 - 61

[\[Abstract\]](#) [\[PDF Full-Text \(664 KB\)\]](#) **IEEE JNL**

2 Process performance monitoring using multivariate statistical process control

Martin, E.B.; Morris, A.J.; Zhang, J.;

Control Theory and Applications, IEE Proceedings- , Volume: 143 , Issue: 2 , 1996

Pages:132 - 144

[\[Abstract\]](#) [\[PDF Full-Text \(1316 KB\)\]](#) **IEE JNL**

3 Using PCA to model shape for process control

Crida, R.C.; Stoddart, A.J.; Illingworth, J.;

3-D Digital Imaging and Modeling, 1997. Proceedings., International Conference on Recent Advances in , 12-15 May 1997

Pages:318 - 325

[\[Abstract\]](#) [\[PDF Full-Text \(904 KB\)\]](#) **IEEE CNF**

4 Modeling and filtering of optical emission spectroscopy data for plasma etching systems

Rangan, S.; Spanos, C.; Poolla, K.;

Semiconductor Manufacturing Conference Proceedings, 1997 IEEE International

Symposium on , 6-8 Oct. 1997
Pages:B41 - B44

[\[Abstract\]](#) [\[PDF Full-Text \(380 KB\)\]](#) IEEE CNF

5 Modeling and filtering of optical emission spectroscopy. Data for plasma etching systems

Rangan, S.; Spanos, C.; Poola, K.;

American Control Conference, 1997. Proceedings of the 1997 , Volume: 1 , 4-June 1997

Pages:627 - 628 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(180 KB\)\]](#) IEEE CNF

6 Recent experiences in the industrial exploitation of principal component based fault detection methods

Lennox, B.;

Computer Aided Control System Design, 2002. Proceedings. 2002 IEEE International Symposium on , 18-20 Sept. 2002

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7 A new fault detection and diagnosis method based on principal component analysis in multivariate continuous processes

Yang Yinghua; Lu Ningyun; Wang Fuli; Ma Liling;

Intelligent Control and Automation, 2002. Proceedings of the 4th World Congress on , Volume: 4 , 10-14 June 2002

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[\[Abstract\]](#) [\[PDF Full-Text \(499 KB\)\]](#) IEEE CNF

8 Neural network modeling of reactive ion etching using principal component analysis of optical emission spectroscopy data

Hong, S.J.; May, G.S.;

Advanced Semiconductor Manufacturing 2002 IEEE/SEMI Conference and Workshop , 30 April-2 May 2002

Pages:415 - 420

[\[Abstract\]](#) [\[PDF Full-Text \(587 KB\)\]](#) IEEE CNF

9 Principal component analysis for errors-in-variables subspace identification

Jin Wang; Qin, S.J.;

Decision and Control, 2001. Proceedings of the 40th IEEE Conference on , Vol 4 , 4-7 Dec. 2001

Pages:3936 - 3941 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(247 KB\)\]](#) IEEE CNF

10 An approach for relating model parameter variabilities to process fluctuations

Power, J.A.; Mathewson, A.; Lane, W.A.;

Microelectronic Test Structures, 1993. ICMTS 1993. Proceedings of the 1993 International Conference on , 22-25 March 1993
Pages:63 - 68

[\[Abstract\]](#) [\[PDF Full-Text \(440 KB\)\]](#) [IEEE CNF](#)

11 A statistical perspective of neural networks for process modeling and control

Qin, S.J.;

Intelligent Control, 1993., Proceedings of the 1993 IEEE International Symposium on , 25-27 Aug. 1993

Pages:599 - 604

[\[Abstract\]](#) [\[PDF Full-Text \(472 KB\)\]](#) [IEEE CNF](#)

12 Statistical approaches to industrial process plant modelling

Hartnett, M.; Irwin, G.W.;

Multidimensional Systems: Problems and Solutions (Ref. No. 1998/225), IEE Colloquium on , 14 Jan. 1998

Pages:7/1 - 7/8

[\[Abstract\]](#) [\[PDF Full-Text \(528 KB\)\]](#) [IEEE CNF](#)

13 Fault diagnosis in industrial process manufacturing using MSPC

Weighell, M.; Martin, E.B.; Morris, A.J.;

Fault Diagnosis in Process Systems (Digest No: 1997/174), IEE Colloquium on April 1997

Pages:4/1 - 4/3

[\[Abstract\]](#) [\[PDF Full-Text \(252 KB\)\]](#) [IEEE CNF](#)

14 Statistical worst-case simulation for CMOS technology

Welten, M.; Clancy, R.; Power, J.A.; Mason, B.; Stribley, P.; Mathewson, A.;
Improving the Efficiency of IC Manufacturing Technology, IEE Colloquium on , Apr 1995

Pages:4/1 - 4/3

[\[Abstract\]](#) [\[PDF Full-Text \(220 KB\)\]](#) [IEEE CNF](#)

15 Multivariate statistics and neural networks in process fault detection

Martin, E.B.; Morris, A.J.;

Qualitative and Quantitative Modelling Methods for Fault Diagnosis, IEE Colloquium on , 24 Apr 1995

Pages:7/1 - 7/8

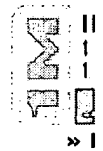
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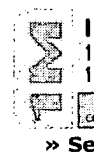
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1 Fusion of fuzzy/neuro/evolutionary computing for knowledge acquisition
Furuhashi, T.;

Proceedings of the IEEE , Volume: 89 , Issue: 9 , Sept. 2001

Pages:1266 - 1274

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) **IEEE JNL**
2 Applications of principal component analysis and factor analysis in the identification of multivariable systems
Priestley, M.; Rao, T.; Tong, H.;

Automatic Control, IEEE Transactions on , Volume: 19 , Issue: 6 , Dec 1974

Pages:730 - 734

[\[Abstract\]](#) [\[PDF Full-Text \(552 KB\)\]](#) **IEEE JNL**
3 Principal component analysis in linear systems: Controllability, observability, and model reduction
Moore, B.;

Automatic Control, IEEE Transactions on , Volume: 26 , Issue: 1 , Feb 1981

Pages:17 - 32

[\[Abstract\]](#) [\[PDF Full-Text \(1296 KB\)\]](#) **IEEE JNL**
4 On the structure of balanced and other principal representations for systems
Fernando, K.; Nicholson, H.;

Automatic Control, IEEE Transactions on , Volume: 28 , Issue: 2 , Feb 1983

Pages:228 - 231

[\[Abstract\]](#) [\[PDF Full-Text \(416 KB\)\]](#) [IEEE JNL](#)

5 Principal component analysis of flexible systems--Open-loop case
Jonckheere, E.;

Automatic Control, IEEE Transactions on , Volume: 29 , Issue: 12 , Dec 1984
 Pages:1095 - 1097

[\[Abstract\]](#) [\[PDF Full-Text \(352 KB\)\]](#) [IEEE JNL](#)

6 Coffee analysis with an electronic nose

Pardo, M.; Sberveglieri, G.;

Instrumentation and Measurement, IEEE Transactions on , Volume: 51 , Issue: 6 , Dec. 2002
 Pages:1334 - 1339

[\[Abstract\]](#) [\[PDF Full-Text \(376 KB\)\]](#) [IEEE JNL](#)

7 A study of the motion and deformation of the heart due to respiration

McLeish, K.; Hill, D.L.G.; Atkinson, D.; Blackall, J.M.; Razavi, R.;

Medical Imaging, IEEE Transactions on , Volume: 21 , Issue: 9 , Sept. 2002
 Pages:1142 - 1150

[\[Abstract\]](#) [\[PDF Full-Text \(706 KB\)\]](#) [IEEE JNL](#)

8 Real-time furnace modeling and diagnostics

Jiangxin Wang; Spanos, C.J.;

Semiconductor Manufacturing, IEEE Transactions on , Volume: 15 , Issue: 4 , 2002
 Pages:393 - 403

[\[Abstract\]](#) [\[PDF Full-Text \(587 KB\)\]](#) [IEEE JNL](#)

9 3-D underwater object recognition

Boulinguez, D.; Quinquis, A.;

Oceanic Engineering, IEEE Journal of , Volume: 27 , Issue: 4 , Oct. 2002
 Pages:814 - 829

[\[Abstract\]](#) [\[PDF Full-Text \(884 KB\)\]](#) [IEEE JNL](#)

10 Analytic PCA construction for theoretical analysis of lighting variations in images of a Lambertian object

Ramamoorthi, R.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 24 , Issue: 10 , Oct. 2002
 Pages:1322 - 1333

[\[Abstract\]](#) [\[PDF Full-Text \(564 KB\)\]](#) [IEEE JNL](#)

11 Face recognition by independent component analysis

Bartlett, M.S.; Movellan, J.R.; Sejnowski, T.J.;

Neural Networks, IEEE Transactions on , Volume: 13 , Issue: 6 , Nov. 2002
 Pages:1450 - 1464

[\[Abstract\]](#) [\[PDF Full-Text \(1405 KB\)\]](#) [IEEE JNL](#)

12 Application of time-frequency principal component analysis to text-independent speaker identification

Magrin-Chagnolleau, I.; Durou, G.; Bimbot, F.;

Speech and Audio Processing, IEEE Transactions on , Volume: 10 , Issue: 6 , : 2002

Pages:371 - 378

[\[Abstract\]](#) [\[PDF Full-Text \(295 KB\)\]](#) [IEEE JNL](#)

13 Medical diagnosis with the gradient microarray of the KAMINA

Koronczi, I.; Ziegler, K.; Kruger, U.; Goschnick, J.;

Sensors Journal, IEEE , Volume: 2 , Issue: 3 , June 2002

Pages:254 - 259

[\[Abstract\]](#) [\[PDF Full-Text \(266 KB\)\]](#) [IEEE JNL](#)

14 Classification of bacteria responsible for ENT and eye infections using the Cyranose system

Boilot, P.; Hines, E.L.; Gardner, J.W.; Pitt, R.; John, S.; Mitchell, J.; Morgan, I.

Sensors Journal, IEEE , Volume: 2 , Issue: 3 , June 2002

Pages:247 - 253

[\[Abstract\]](#) [\[PDF Full-Text \(269 KB\)\]](#) [IEEE JNL](#)

15 A portable electronic nose based on embedded PC technology and GNU/Linux: hardware, software and applications

Perera, A.; Sundic, T.; Pardo, A.; Gutierrez-Osuna, R.; Marco, S.;

Sensors Journal, IEEE , Volume: 2 , Issue: 3 , June 2002

Pages:235 - 246

[\[Abstract\]](#) [\[PDF Full-Text \(402 KB\)\]](#) [IEEE JNL](#)

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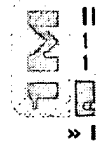
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 Zhang Xinhua; Zhang Anqing; Fang Jianping; Yang Shaoqing;
 Signal Processing Proceedings, 2000. WCCC-ICSP 2000. 5th International
 Conference on , Volume: 3 , 21-25 Aug. 2000
 Pages:1802 - 1805 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(196 KB\)\]](#) **IEEE CNF**
2 A kernel based nonlinear subspace projection method for reduction of hyperspectral image dimensionality

 Yanfeng Gu; Ye Zhang; Junping Zhang;
 Image Processing. 2002. Proceedings. 2002 International Conference on , Vol.
 2 , 22-25 Sept. 2002
 Pages:II-357 - II-360 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(406 KB\)\]](#) **IEEE CNF**
3 A developing sensory mapping for robots

 Zhang, N.; Weng, J.; Zhang, Z.;
 Development and Learning, 2002. Proceedings. The 2nd International Conference
 on , 12-15 June 2002
 Pages:13 - 20

[\[Abstract\]](#) [\[PDF Full-Text \(399 KB\)\]](#) **IEEE CNF**
4 Adaptive subspace decomposition for hyperspectral data dimensionality reduction

 Ye Zhang; Desai, M.D.; Junping Zhang; Ming Jin;
 Image Processing, 1999. ICIP 99. Proceedings. 1999 International Conference
 on , Volume: 2 , 24-28 Oct. 1999

Pages:326 - 329 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(376 KB\)\]](#) IEEE CNF

5 Automatic image orientation detection

Vailaya, A.; Zhang, H.; Changjiang Yang; Feng-I Liu; Jain, A.K.;
Image Processing, IEEE Transactions on , Volume: 11 , Issue: 7 , July 2002
Pages:746 - 755

[\[Abstract\]](#) [\[PDF Full-Text \(388 KB\)\]](#) IEEE JNL

6 Adaptive RLS algorithm for blind source separation using a natural gradient

Xiao-Long Zhu; Xian-Da Zhang;
Signal Processing Letters, IEEE , Volume: 9 , Issue: 12 , Dec. 2002
Pages:432 - 435

[\[Abstract\]](#) [\[PDF Full-Text \(288 KB\)\]](#) IEEE JNL

7 A class of learning algorithms for principal component analysis and minor component analysis

Qingfu Zhang; Yiu Wing Leung;
Neural Networks, IEEE Transactions on , Volume: 11 , Issue: 1 , Jan. 2000
Pages:200 - 204

[\[Abstract\]](#) [\[PDF Full-Text \(144 KB\)\]](#) IEEE JNL

8 A class of learning algorithms for principal component analysis and minor component analysis

Zhang, Q.; Yiu-Wung Leung;
Neural Networks, IEEE Transactions on , Volume: 11 , Issue: 2 , March 2000
Pages:529 - 533

[\[Abstract\]](#) [\[PDF Full-Text \(144 KB\)\]](#) IEEE JNL

9 Handwritten digit recognition by adaptive-subspace self-organizing (ASSOM)

Bailing Zhang; Minyue Fu; Hong Yan; Jabri, M.A.;
Neural Networks, IEEE Transactions on , Volume: 10 , Issue: 4 , July 1999
Pages:939 - 945

[\[Abstract\]](#) [\[PDF Full-Text \(248 KB\)\]](#) IEEE JNL

10 Dynamical system for computing the eigenvectors associated with largest eigenvalue of a positive definite matrix

Bingfu Zhang; Zheng Bao;
Neural Networks, IEEE Transactions on , Volume: 6 , Issue: 3 , May 1995
Pages:790 - 791

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) IEEE JNL

11 Energy function for the one-unit Oja algorithm

Qingfu Zhang; Yiu-Wing Leung;

Neural Networks, IEEE Transactions on , Volume: 6 , Issue: 5 , Sept. 1995
Pages:1291 - 1293

[\[Abstract\]](#) [\[PDF Full-Text \(264 KB\)\]](#) [IEEE JNL](#)

12 MMP-PCA face recognition method

Guangda Su; Cuiping Zhang; Rong Ding; Cheng Du;
Electronics Letters , Volume: 38 , Issue: 25 , 5 Dec. 2002
Pages:1654 - 1656

[\[Abstract\]](#) [\[PDF Full-Text \(436 KB\)\]](#) [IEEE JNL](#)

13 Process performance monitoring using multivariate statistical process control

Martin, E.B.; Morris, A.J.; Zhang, J.;
Control Theory and Applications, IEE Proceedings- , Volume: 143 , Issue: 2 , 1996
Pages:132 - 144

[\[Abstract\]](#) [\[PDF Full-Text \(1316 KB\)\]](#) [IEEE JNL](#)

14 Population optimization algorithm based on ICA

Qingfu Zhang; Allinson, N.M.; Hujun Yin;
Combinations of Evolutionary Computation and Neural Networks, 2000 IEEE Symposium on , 11-13 May 2000
Pages:33 - 36

[\[Abstract\]](#) [\[PDF Full-Text \(252 KB\)\]](#) [IEEE CNF](#)

15 On the roles of PCA and ICA in data fusion

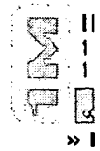
Chen, C.H.; Xiaohui Zhang;
Geoscience and Remote Sensing Symposium, 2000. Proceedings. IGARSS 2000 IEEE 2000 International , Volume: 6 , 24-28 July 2000
Pages:2620 - 2622 vol.6

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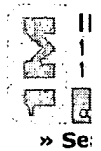
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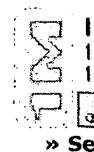
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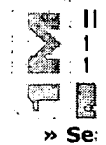
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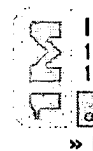
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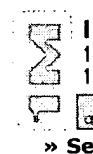
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